

**Search Notes****Application/Control No.**

10/561,442

**Examiner**

CHRIS H. CHU

**Applicant(s)/Patent under  
Reexamination**

ANDRIEU ET AL.

**Art Unit**

2874

**SEARCHED**

Class	Subclass	Date	Examiner
385	124, 126	4/22/2008	/CC/

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
USPTO EAST: USPAT AND US-PGPUB (see attached text)		4/22/2008	/CC/

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
applicant's cited references	4/22/2008	/CC/
text search	4/22/2008	/CC/
IEEE database	4/22/2008	/CC/